

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination MERLAU ET AL.	
		Examiner David L. Vanik	Art Unit 1615	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,136,884	10-2000	Chen et al.	523/105
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*	N	WO 99/63955	11-1999	France	Samain et al.	A61K 7/06
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	X	

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